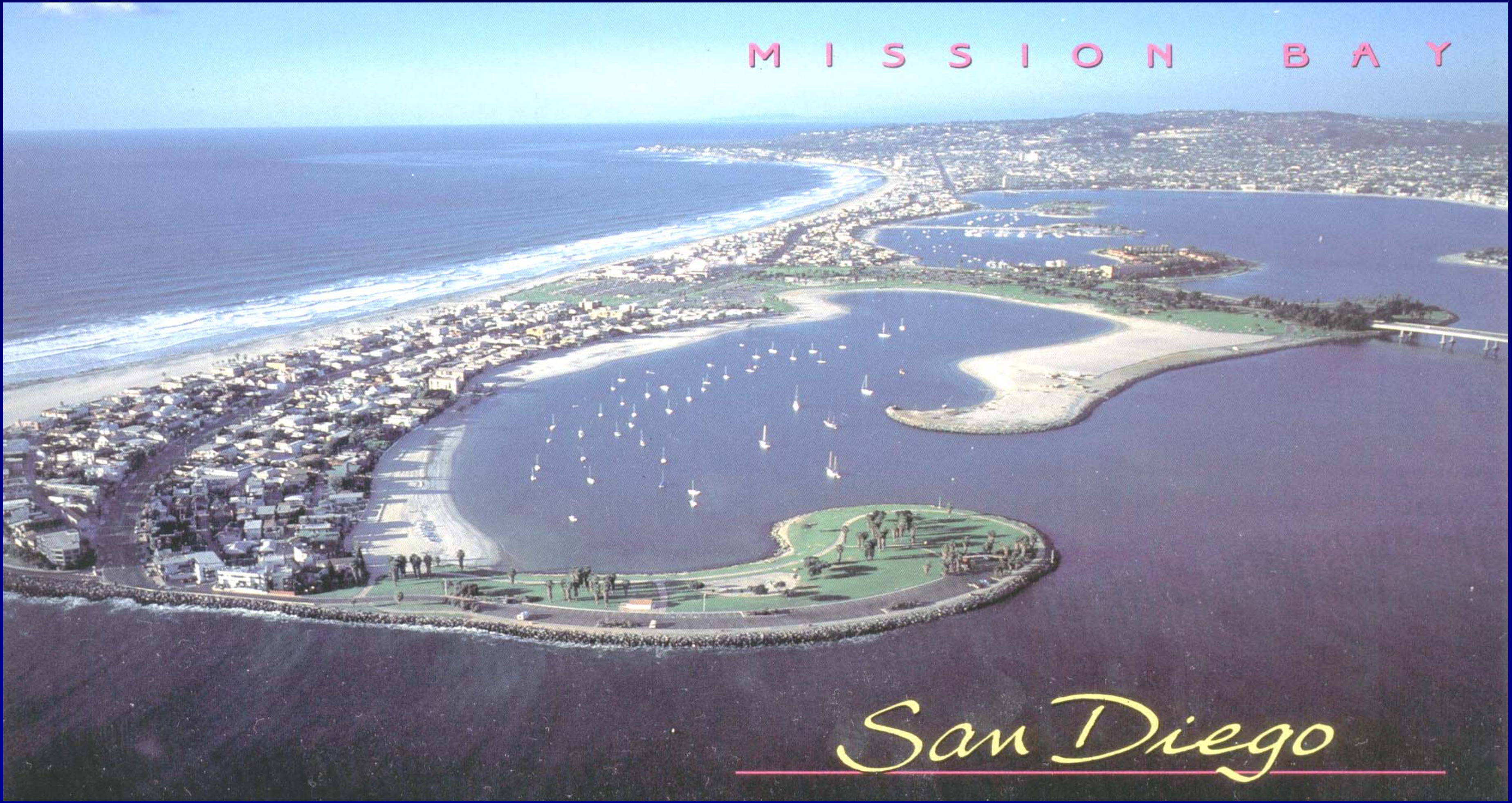
SOUTHWEST TEST WORKSHOP

- To Advance Wafer Test Technology
- To Serve and Inform the Wafer Test Professional
- To Boldly Go Where No Workshop Has Gone Before

San Diego, CA, June 5 to 8, 2005

SOUTHWEST TEST WORKSHOP

15th Annual SWTW



Southwest Test Workshop 200

- “THE” Conference for Wafer Test Professionals
- Sponsored by the IEEE Computer Society and the Test Technology Technical Committee
- Not a theoretical or academic conference
- Not a Sales Show, but we do have exhibits
- It’s a *Probe Technology Forum*
- Provides practical solutions to real problems
- A balance mixture of semiconductor manufacturer and supplier presentations

Informal Conference

- Long Breaks
- Plenty of networking opportunities
- Informal discussions
- Great social activities
- Meet new people & ***have some fun!***

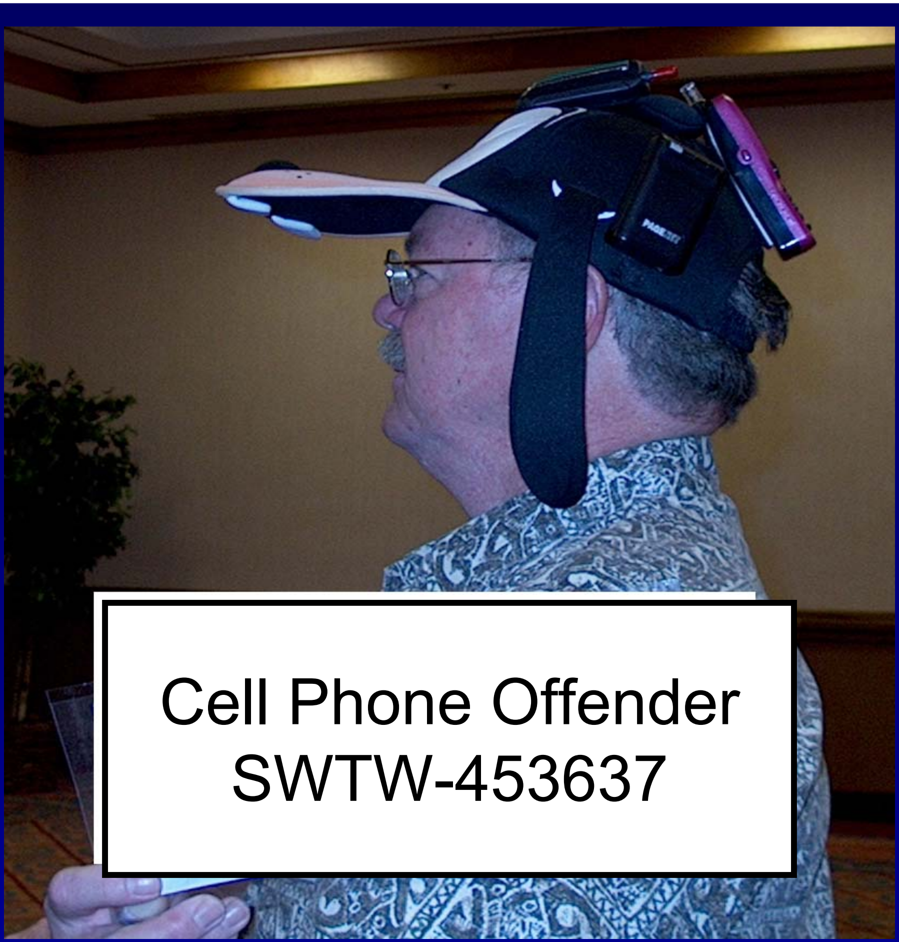
(Don't tell the IEEE about the fun part)

“Who's fault is it?”

- **Organization and Technical Program**
  - William Mann, SWTW General Chair
  - Jerry Broz, Ph.D., International Test Solutions, Program Chair
  - Maddie Harwood, CEM Inc, Registration and Finance Chair
  - Megan White, Exhibits Coordinator
- **Steering Committee and Session Chairs**
  - Michael Egloff, AMD
  - Michael Harris, Texas Instruments
  - Ken Karklin, Agilent Technologies
  - Ger Koch, Philips Semiconductor
  - Rey Rincon, Kulicke and Soffa
  - Bill Williams, Freescale (Retired)
  - Phil Seitzer, Agere (Retired)
  - Roger Sinsheimer, Xandex
  - Tim Swettlen, Intel
  - Fred Taber, IBM (Retired)
  - Jack Courtney, IBM
  - Scott Mitchell, Texas Instruments

Silence your cell phone !!!

Cell Phone Offender
SWTW-453637



Cell Phone Offender
SWTW-453637

Technical Program

- **Sunday, June 5, 2005**
  - High Power Probing
  - Registration & Exhibits
  - Dinner
  - Keynote Speaker:

Igor Khandros, Ph.D.

Founder and CEO of FormFactor

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Technical Program

- **Monday, June 6**
  - Continental Breakfast
  - Modeling to Reduce Dielectric Cracking
  - Reducing Probe Test Cost
  - Lunch
  - Probe Potpourri
  - New Probe Technologies
  - Exhibits open from 5:00 t0 7:00 PM
  - Dinner
  - Informal discussions at the “Barefoot Bar”

Technical Program

- Tuesday, June 7
  - Continental Breakfast
  - On The Road To Full Wafer Test
  - Minimizing Contact Resistance Instability
  - Lunch
  - Free Afternoon for Networking
  - Exhibits open from 4:00 PM to 6:00 PM
  - Busses leave at 6:00 PM for USS Midway

Technical Program

- Wednesday, June 8
  - Continental Breakfast
  - Probe Process Characterization
  - Probe Test Data Management
  - Best Presentation Awards
  - Adjournment and Lunch

http://www.swtest.org

- Central Online Repository
  - Past presentations
  - Online registration
  - Sign up for our mailing list
  - With more features to come……..
- Tremendous continued success!!
  - Over sixty-two thousand visits
  - Thanks to "web-efforts" of Jerry Broz

Recognition & Awards

- IEEE Recognition
- First SWTW Life Achievement
- Best Overall Presentation
- Best Data Presented
- Best Presentation, Tutorial in Nature
- Most "Inspirational" Presentation

- Other "Special Awards"

“Special” Award

“ROYAL ORDER OF THE GOLDEN WHEELBARROW FULL OF CRAP”

The Poorest Disguised Sales Pitch Hall of Shame

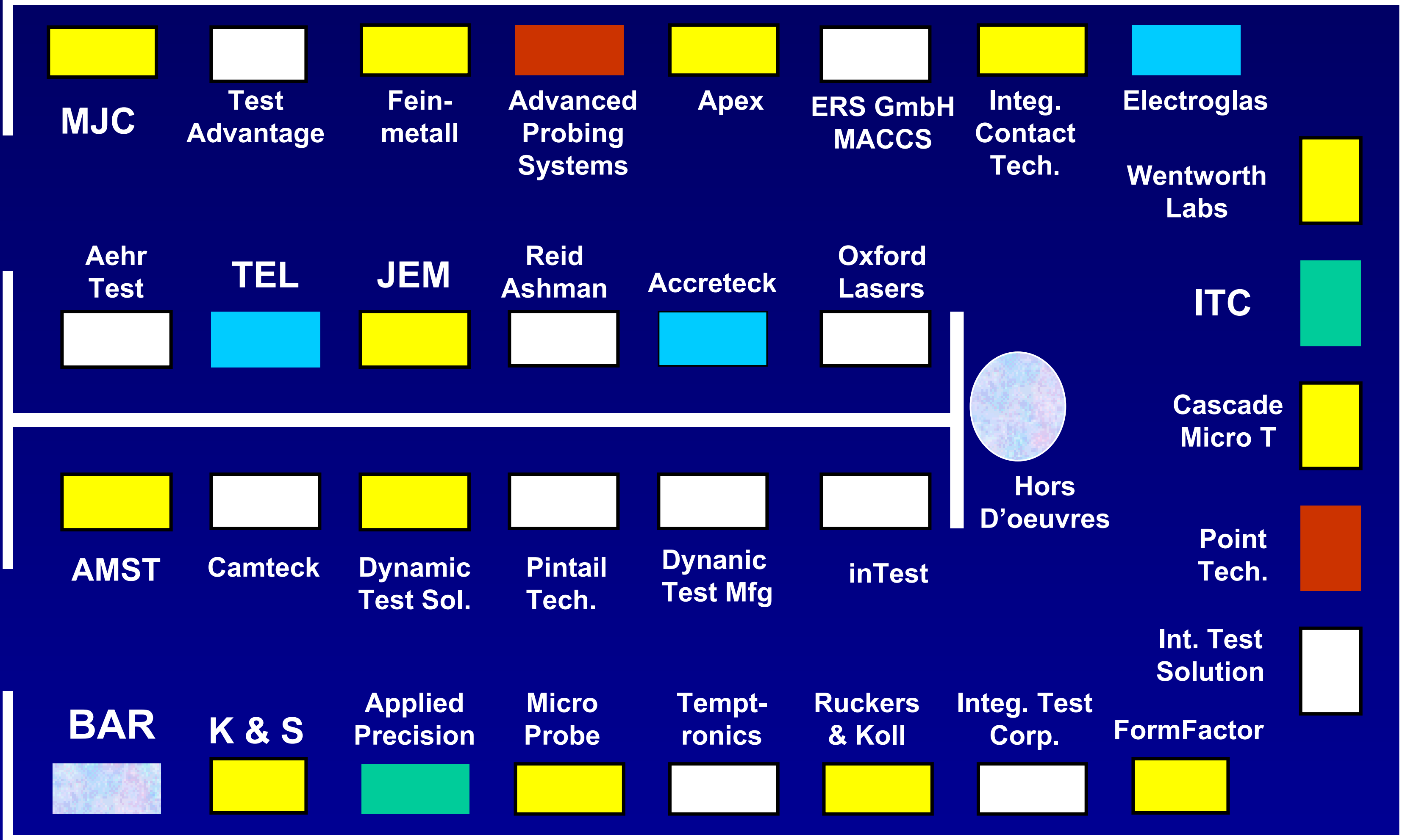
Tabletop Exhibits

Applied Precision, LLC
Wentworth Laboratories Inc.
Micronics Japan Co., Ltd.
International Test Solutions
Advanced Probing Systems, Inc.
Integrated Technology Corp.
Cascade Microtech, Inc
Integrated Test Corporation
Dynalyst Manufacturing Corp.
Temptronic Corporation
International Contact Tech..

Electroglas, Inc.
JEM America Corp.
Accretech USA, Inc
MACSS, LLC
Oxford Lasers
Microprobe
Apex America
AMST Co. Ltd.
Camtek USA, Inc.
Rucker & Kolls
Pintail Technologies

InTest Corp.
FormFactor
Feinmetall GmbH
Test Advantage, Inc.
Kulicke & Soffa
Dynamic Test Solutions
Reid-Ashman Mfg.
Aehr Test Systems
Tokyo Electron America
Point Technologies

Exhibits Floor Plan



MJC

Test Advantage

Fein-metall

Advanced Probing Systems

Apex

ERS GmbH MACCS

Integ. Contact Tech.

Electroglas

Wentworth Labs

Aehr Test

TEL

JEM

Reid Ashman

Accreteck

Oxford Lasers

ITC

Cascade Micro T

Hors D’oeuvres

AMST

Camteck

Dynamic Test Sol.

Pintail Tech.

Dynanic Test Mfg

inTest

Point Tech.

Int. Test Solution

BAR

K & S

Applied Precision

Micro Probe

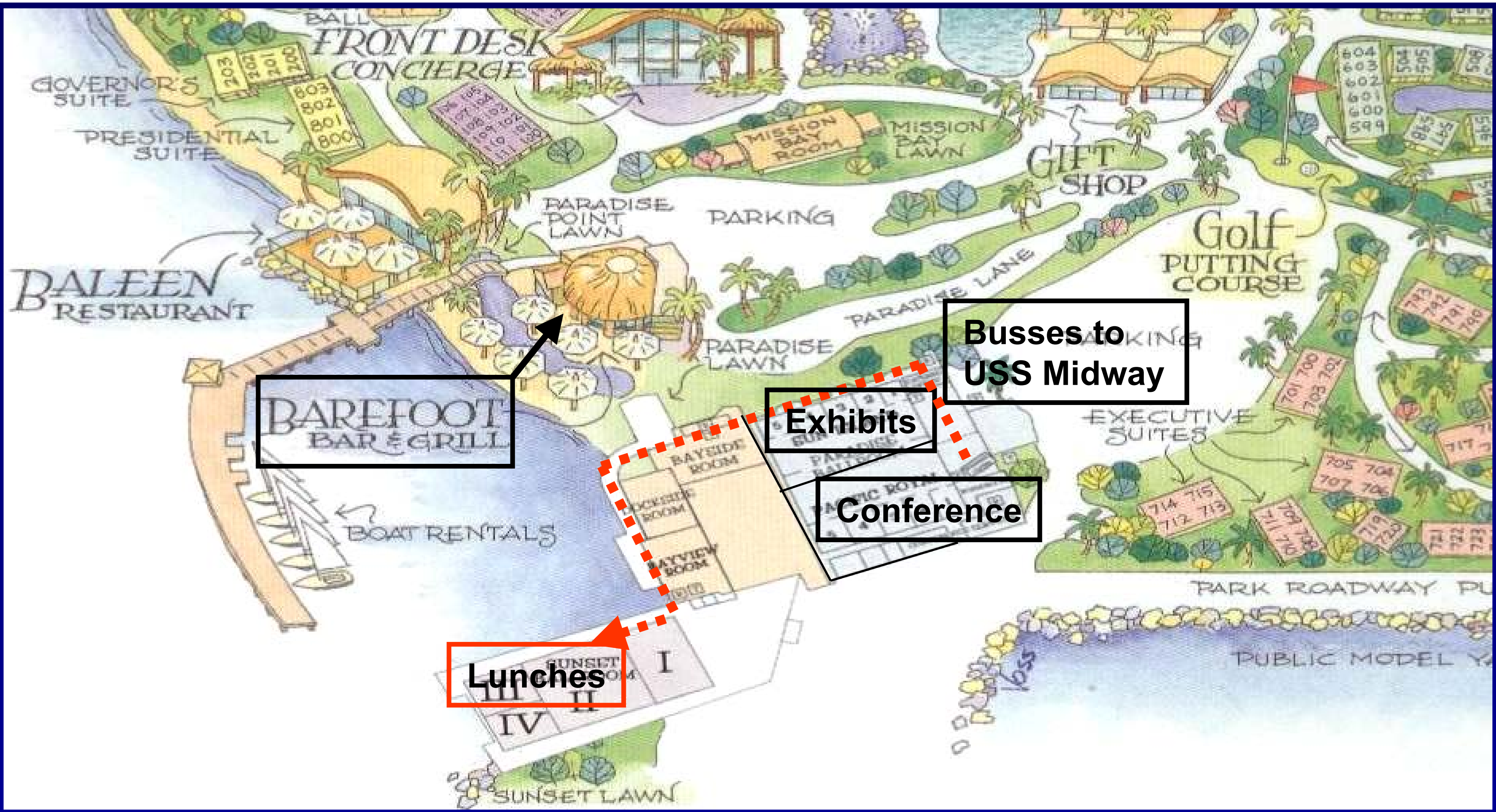
Tempt-ronics

Ruckers & Koll

Integ. Test Corp.

FormFactor

Don’t Get Lost!



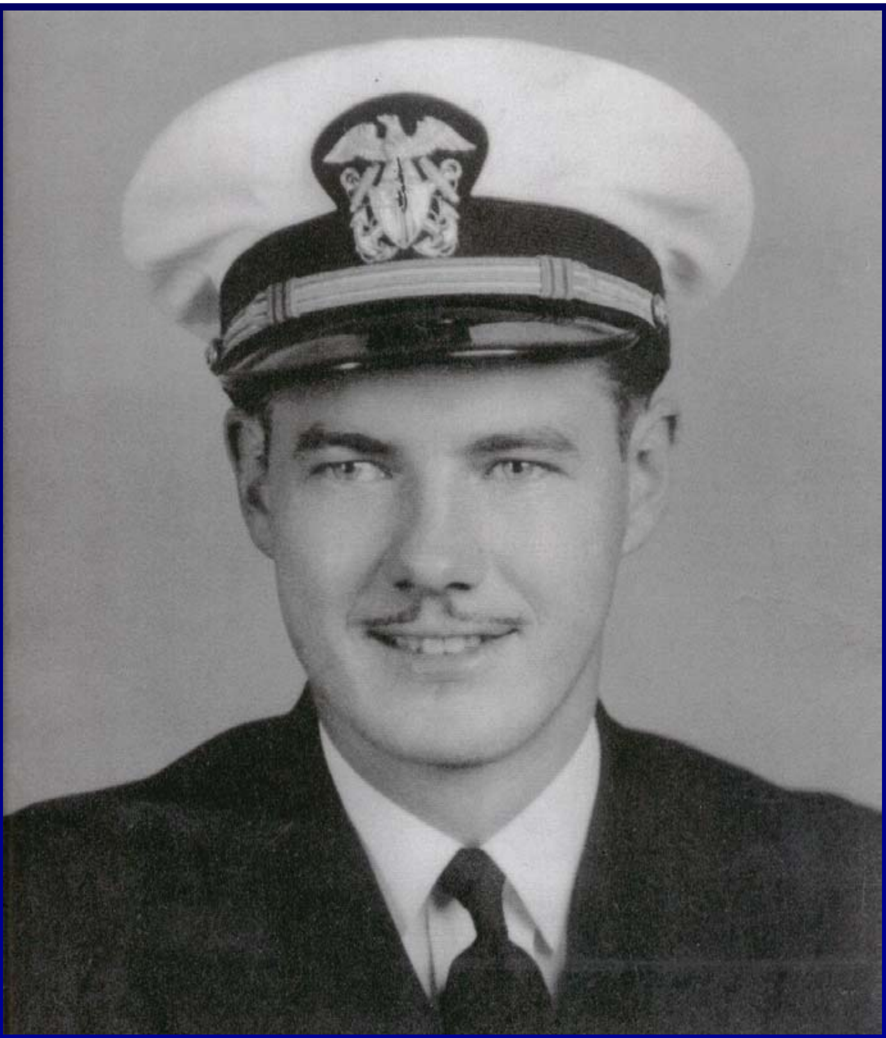
Busses to USS Midway

Exhibits

Conference

Lunches

Lieutenant William L. Mann, US Navy, Retired 1946



“Son, what did you say you rented?”

USS Midway Aircraft Carrier

SOUTHWEST TEST WORKSHOP

A Social Event to Remember

- Busses depart Tuesday at 1800 hours
- Cocktails at sunset on the Flight Deck
- Tour of the ship
    - Bridge
    - Aircraft Launch and Recovery Tower
    - Galley
    - Officer’s and Enlisted Men’s Quarters
    - Sickbay
    - Twelve position Computer Flight Simulator
- Dinner on the Hangar Deck

Probe Market Overview

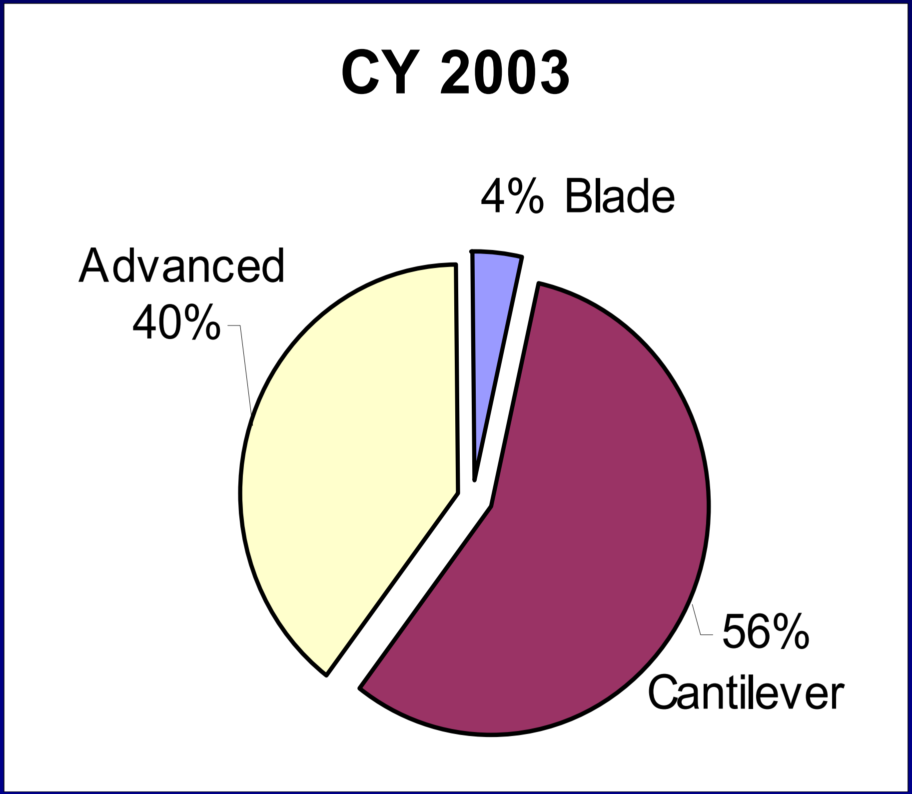
Special thanks to
Bob Mariner
VLSI Research

The complete “2004 Probe Market Survey” can be purchased at www.vlsiresearch.com

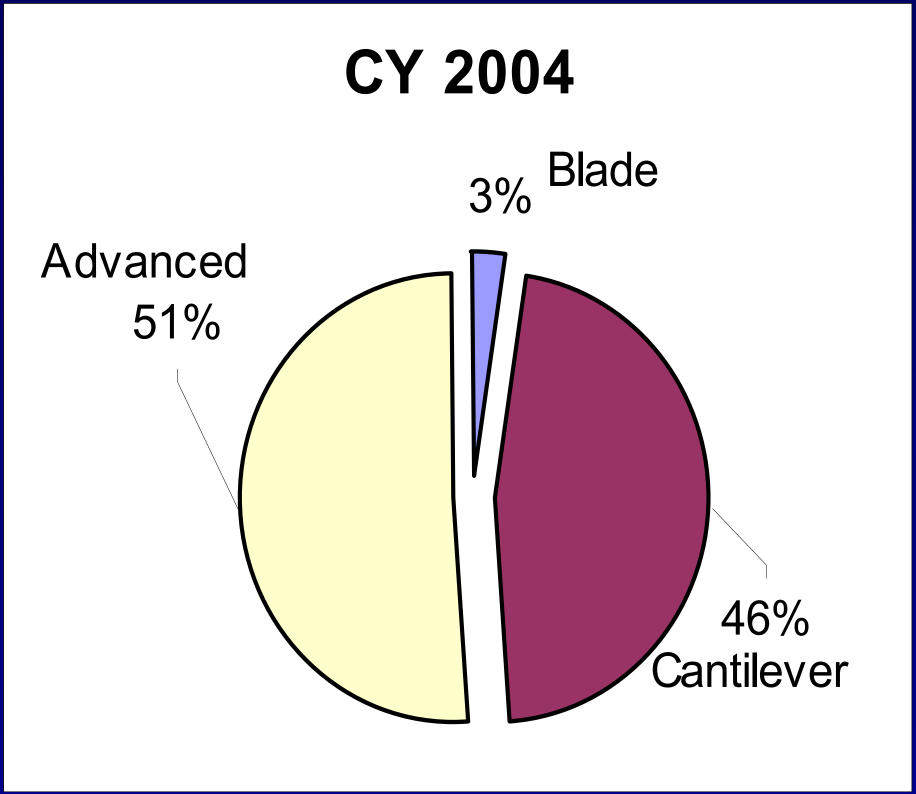
Top Probe Card Suppliers

1. FormFactor	$178 M
2. Japan Electronic Materials	$116 M
3. Kulicke & Soffa	$ 65 M
4. Micronics Japan Co.	$ 65 M
5. Tokyo Cathode Laboratory	$ 28 M
6. MPI	$ 21 M
6. Technoprobe	$ 21 M
8. SV Probe	$ 20 M
9. Feinmetall GmbH	$ 19 M
10. Microprobe	$ 18 M

Revenue By Technology

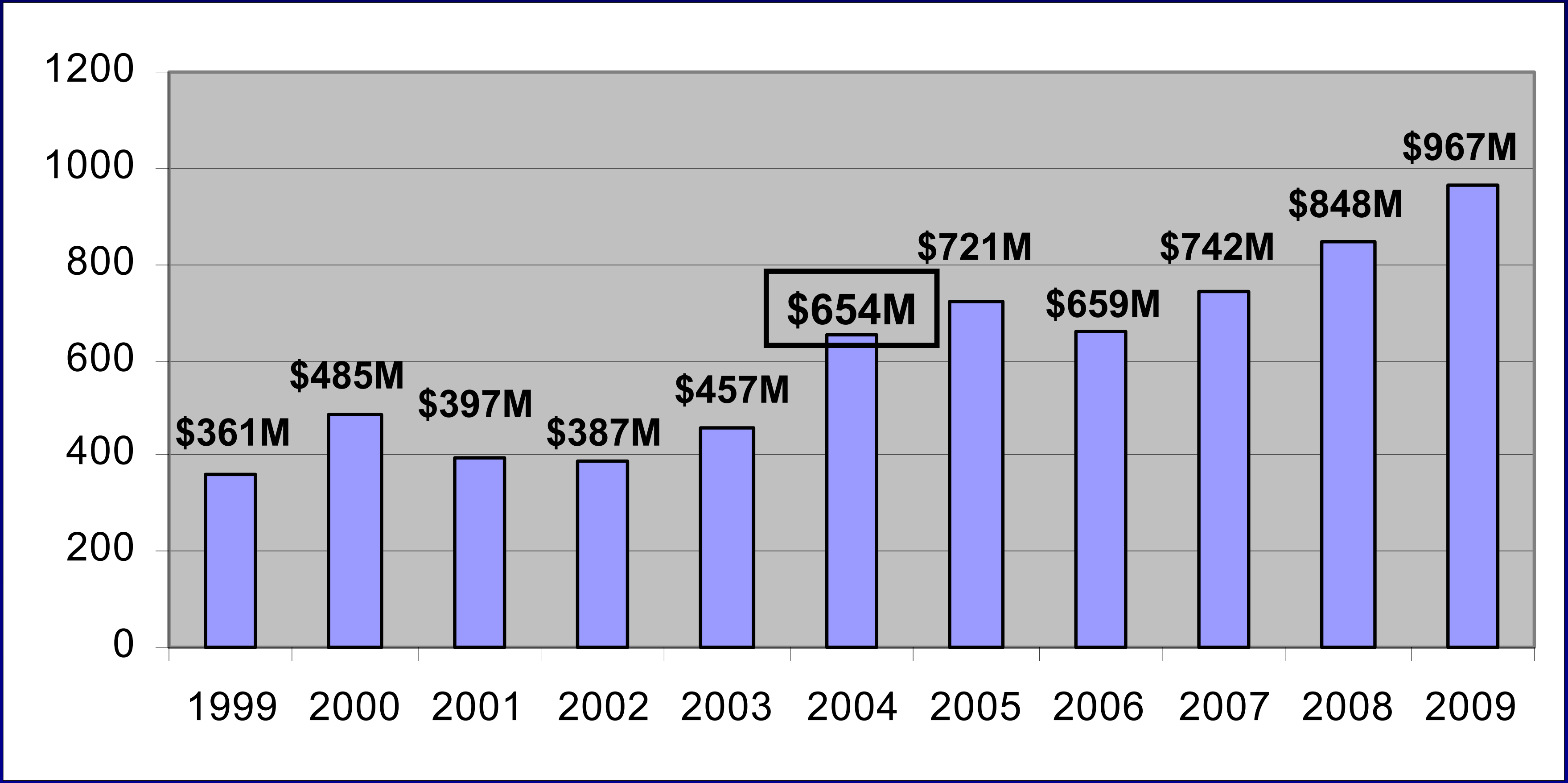


$457 M



$654 M

Total Probe Card Revenue



Revenue in Million US $; Semiconductor Segment Only

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